DS05-11138-1E

# MEMORY **Un-buffered** $16 \text{ M} \times 64 \text{ BIT}$ SYNCHRONOUS DYNAMIC RAM DIMM

# MB8516S064CZ-102/-103/-102L/-103L

### 168-pin, 4 Clock, 2-bank, based on 8 M × 8 Bit SDRAMs with SPD

### DESCRIPTION

The Fujitsu MB8516S064CZ is a fully decoded, CMOS Synchronous Dynamic Random Access Memory (SDRAM) Module consisting of sixteen MB81F64842C devices which organized as four banks of 8 M × 8 bits and a 2K-bit serial EEPROM on a 168-pin glass-epoxy substrate.

The MB8516S064CZ features a fully synchronous operation referenced to a positive edge clock whereby all operations are synchronized at a clock input which enables high performance and simple user interface coexistence.

The MB8516S064CZ is optimized for those applications requiring high speed, high performance and large memory storage, and high density memory organizations.

This module is ideally suited for workstations, PCs, laser printers, and other applications where a simple interface is needed.

## PRODUCT LINE & FEATURES

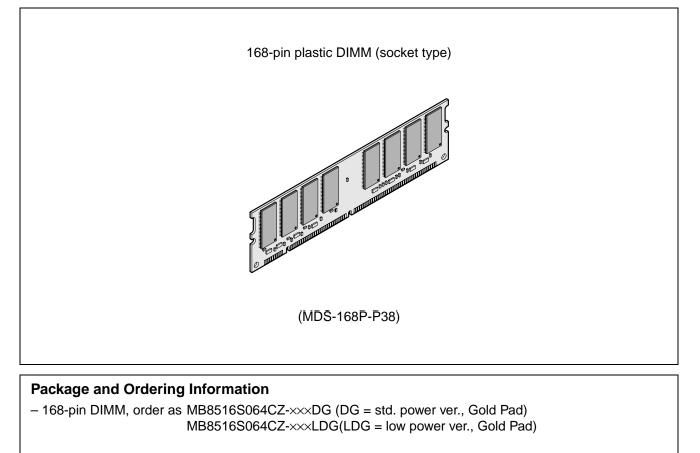
Para	meter	MB8516S064CZ-102/-102L	MB8516S064CZ-103/-103L
CL-trcd-trp		2-2-2 clk min.	3-2-2 clk min.
Clock Frequency		100 MHz max.	100 MHz max.
Burst Mode Cycle Time		10 ns min.	10 ns min.
Output Valid from Clo	ck	6 ns max. (CL = 2)	6 ns max. (CL = 3)
	Two Banks Active	5904 mW max.	5904 mW max.
Power Dissipation	Self Refresh Mode	57.6 mW max. (std. power) 28.8 mW max. (low power)	57.6 mW max. (std. power) 28.8 mW max. (low power)

 Un-buffered 168-pin DIMM Socket Type (Lead pitch: 1.27 mm)

- Conformed to JEDEC Standard (4 CLK)
- Organization: 16,777,216 words  $\times 64$  bits
- 3.3 V ±0.3 V Supply Voltage
- All input/output LVTTL compatible
- Conformed to Intel PC/100 spec

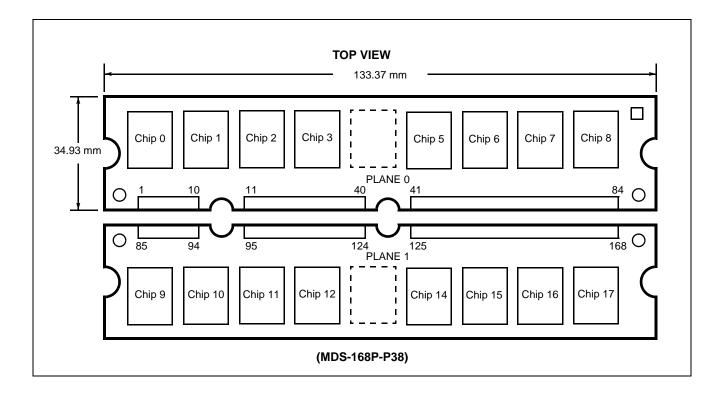
- 4096 Refresh Cycle every 65.6 ms
- Auto and Self Refresh
- CKE Power Down Mode
- DQM Byte Masking (Read/Write)
- Memory: MB81F64842C (8 M × 8, 4-bank) × 16 pcs Serial Presence Detect (SPD) with Serial EEPROM: Intel SPD spec Rev 1.2A Format
  - Module size: 1.375" (height)  $\times$  5.25" (length)  $\times$  0.157" (thickness)

## ■ PACKAGE



### ■ PIN ASSIGNMENTS

Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name
1	Vss	29	DQMB <sub>1</sub>	57	DQ18	85	Vss	113	DQMB₅	141	DQ50
2	DQ <sub>0</sub>	30	CS <sub>0</sub>	58	DQ19	86	DQ32	114	CS <sub>1</sub>	142	DQ <sub>51</sub>
3	DQ <sub>1</sub>	31	N.C.	59	Vcc	87	DQ33	115	RAS	143	Vcc
4	DQ <sub>2</sub>	32	Vss	60	DQ20	88	DQ34	116	Vss	144	DQ <sub>52</sub>
5	DQ <sub>3</sub>	33	Ao	61	N.C.	89	DQ35	117	<b>A</b> 1	145	N.C.
6	Vcc	34	A <sub>2</sub>	62	N.C.	90	Vcc	118	Аз	146	N.C.
7	DQ4	35	A4	63	CKE1	91	DQ <sub>36</sub>	119	A5	147	N.C.
8	DQ₅	36	A <sub>6</sub>	64	Vss	92	DQ <sub>37</sub>	120	A7	148	Vss
9	DQ <sub>6</sub>	37	A8	65	DQ <sub>21</sub>	93	DQ38	121	A9	149	DQ <sub>53</sub>
10	DQ7	38	A10	66	DQ22	94	DQ39	122	BA <sub>0</sub>	150	DQ <sub>54</sub>
11	DQ8	39	BA₁	67	DQ23	95	DQ40	123	A11	151	DQ55
12	Vss	40	Vcc	68	Vss	96	Vss	124	Vcc	152	Vss
13	DQ <sub>9</sub>	41	Vcc	69	DQ <sub>24</sub>	97	DQ <sub>41</sub>	125	CLK1	153	DQ56
14	DQ10	42	CLK <sub>0</sub>	70	DQ25	98	DQ <sub>42</sub>	126	N.C.	154	DQ57
15	DQ11	43	Vss	71	DQ <sub>26</sub>	99	DQ <sub>43</sub>	127	Vss	155	DQ <sub>58</sub>
16	DQ12	44	N.C.	72	DQ27	100	DQ44	128	CKE <sub>0</sub>	156	DQ59
17	DQ13	45	CS <sub>2</sub>	73	Vcc	101	DQ <sub>45</sub>	129	<u>CS</u> ₃	157	Vcc
18	Vcc	46	DQMB <sub>2</sub>	74	DQ <sub>28</sub>	102	Vcc	130	DQMB <sub>6</sub>	158	DQ60
19	DQ <sub>14</sub>	47	DQMB <sub>3</sub>	75	DQ29	103	DQ <sub>46</sub>	131	DQMB7	159	DQ <sub>61</sub>
20	DQ15	48	N.C.	76	DQ30	104	DQ <sub>47</sub>	132	N.C.	160	DQ <sub>62</sub>
21	N.C.	49	Vcc	77	DQ <sub>31</sub>	105	N.C.	133	Vcc	161	DQ <sub>63</sub>
22	N.C.	50	N.C.	78	Vss	106	N.C.	134	N.C.	162	Vss
23	Vss	51	N.C.	79	CLK <sub>2</sub>	107	Vss	135	N.C.	163	CLK <sub>3</sub>
24	N.C.	52	N.C.	80	N.C.	108	N.C.	136	N.C.	164	N.C.
25	N.C.	53	N.C.	81	N.C. (WP)	109	N.C.	137	N.C.	165	SA <sub>0</sub>
26	Vcc	54	Vss	82	SDA	110	Vcc	138	Vss	166	SA1
27	WE	55	DQ <sub>16</sub>	83	SCL	111	CAS	139	DQ48	167	SA <sub>2</sub>
28	DQMB <sub>0</sub>	56	DQ17	84	Vcc	112	DQMB <sub>4</sub>	140	DQ49	168	Vcc



### ■ PIN DESCRIPTIONS

Symbol	I/O	Function	Symbol	I/O	Function
A <sub>0</sub> to A <sub>11</sub>	I	Address Input	DQ <sub>0</sub> to DQ <sub>63</sub>	I/O	Data Input/Data Output
RAS	I	Row Address Strobe	Vcc	—	Power Supply (+3.3 V)
CAS	I	Column Address Strobe	Vss	—	Ground (0 V)
WE	Ι	Write Enable	N.C.		No Connection
DQMB <sub>0</sub> to DQMB <sub>7</sub>	I	Data (DQ) Mask	SA <sub>0</sub> to SA <sub>2</sub>	I	Serial PD Address Input
CLK <sub>0</sub> to CLK <sub>3</sub>	I	Clock Input	SCL	I	Serial PD Clock
CKE <sub>0</sub> , CKE <sub>1</sub>	I	Clock Enable	SDA	I/O	Serial PD Address/Data Input/Output
$\overline{CS}_0$ to $\overline{CS}_3$	I	Chip Select	WP	—	Serial PD Write Protect
BA0, BA1	I	Bank Select (Bank Address)			_

### ■ SERIAL-PD INFORMATION

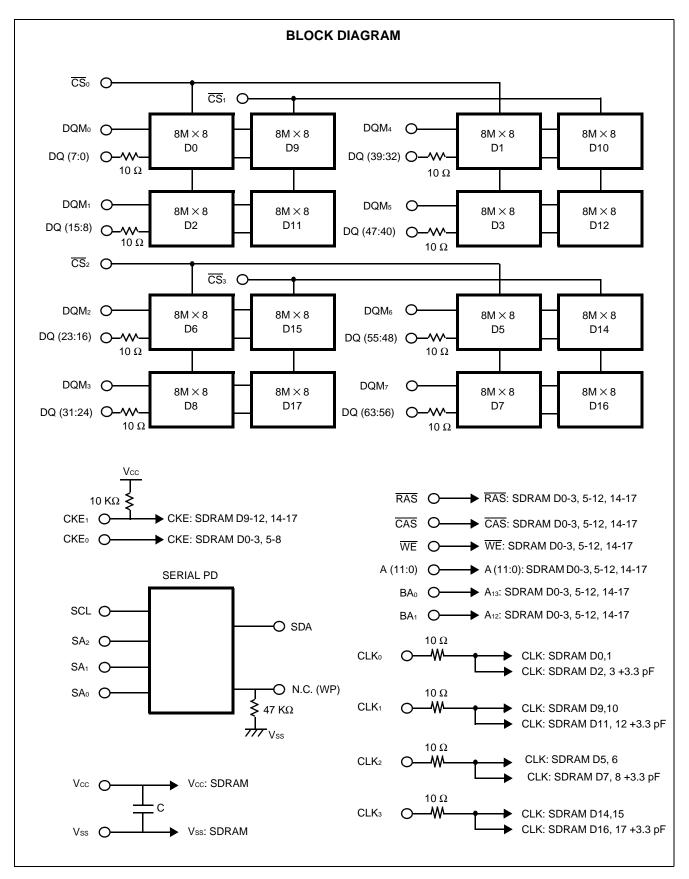
			Hex	Value
Byte	Function Described		-102/ 102L	-103/ 103L
0	Defines Number of Bytes Written into Serial Memory at Module	128 Byte	80h	80h
1 2 3 4 5 6 7	Manufacture Total Number of Bytes of SPD Memory Device Fundamental Memory Type Number of Row Addresses	256 Byte SDRAM 12	08h 04h 0Ch	08h 04h 0Ch
4	Number of Column Addresses	9	09h	09h
5	Number of Module Banks	2 bank	02h	02h
6	Data Width	64 bit	40h	40h
7	Data Width (Continuation)	+0	00h	00h
8	Interface Type	LVTTL	01h	01h
9	SDRAM Cycle Time (Highest CAS Latency)	10/10 ns	A0h	A0h
10	SDRAM Access from Clock (Highest CAS Latency)	6/6 ns	60h	60h
11	DIMM Configuration Type	Non-Parity	00h	00h
12	Refresh Rate/Type	Self, Normal	80h	80h
13	Primary SDRAM Width	×8	08h	08h
14	Error Checking SDRAM Width	0	00h	00h
15	Minimum Clock Delay for Back to Back Random Column Addresses	1 Cycle	01h	01h
16	Burst Lengths Supported	1, 2, 4, 8, Page	8Fh	8Fh
17	Number of Banks on Each SDRAM Device	4 bank	04h	04h
18	CAS Latency Supported	2, 3	06h	06h
19	CS Latency	0	01h	01h
20	Write Latency	0	01h	01h
21	SDRAM Module Attributes	UN-buffer	00h	00h
22	SDRAM Device Attributes : General	*1	0Eh	0Eh
23	SDRAM Cycle Time (2nd. Highest CAS Latency)	10/15 ns	A0h	F0h
24	SDRAM Access from Clock (2nd. Highest CAS Latency)	6/8 ns	60h	80h
25	SDRAM Cycle Time (3rd. Highest CAS Latency)	No Support	00h	00h
26	SDRAM Access from Clock (3rd. Highest CAS Latency)	No Support	00h	00h
27	Minimum Row Precharge Time (trp)	20/20 ns	14h	14h
28	Row Activate to Row Activate Minimum (trrd)	20/20 ns	14h	14h
29	RAS to CAS Delay Min. (trcd)	20/20 ns	14h	14h
30	Minimum RAS Pulse Width	50/50 ns	32h	32h
31	Module Bank Density	64 MByte	10h	10h
32	Command and Address Signal Input Setup Time	2 ns	20h	20h
33	Command and Address Signal Input Hold Time	1 ns	10h	10h
34	Data Signal Input Setup Time	2 ns	20h	20h
35	Data Signal Input Hold Time	1 ns	10h	10h
36 to 61 62 63	Unused Storage Locations SPD Data Revision Code Checksum for Byte 0 to 62	1.2 *2	00h 12h 06h	00h 12h 76h
64 to 71	Manufacturer's JEDEC ID Code Per JEP-108E	Optional	00h	00h
72	Manufacturing Location	Optional	00h	00h
73 to 90	Manufacturer's Part Number	Optional	00h	00h
91 to 92	Revision Code	Optional	00h	00h
93 to 94	Manufacturing Data	Optional	00h	00h
95 to 98	Assembly Serial Number	Optional	00h	00h
99 to 125	Manufacturer Specific Data	Optional	00h	00h
126	Intel Specification Frequency	100 MHz	64h	64h
127	Intel Specification Details for 100 MHz Support	CL = 2, 3 / 3	FFh	FDh
128+	Unused Storage Locations	—		

Note: Any write operation must NOT be executed into the addresses of Byte 0 to Byte 127. Some or all data stored into Byte 0 to Byte 127 may be broken.

\*1. Byte 22: SDRAM Device Attributes

Bit7	Bit6	Bit5	Bit4	Bit3	Bit2	Bit1	Bit0
TBD	TBD	Upper Vcc tolerance	Lower Vcc tolerance	Supports Write 1 /Read Burst	Supports Precharge All	Supports Auto- Precharge	Suppo <u>rts</u> Early RAS Precharge
0	0	0	0	1	1	1	0

\*2. Byte 63: Checksum for Byte 0 to 62 This byte is the checksum for Byte 0 through 62. This byte contains the value of the low 8-bits of the arithmetic sum of Byte 0 through 62.



### ■ ABSOLUTE MAXIMUM RATINGS (See WARNING)

Parameter	Symbol	Va	lue	l Init
Parameter	Symbol	Min.	Max.	Unit
Supply Voltage*	Vcc	-0.5	+4.6	V
Input Voltage*	VIN	-0.5	+4.6	V
Output Voltage*	Vout	-0.5	+4.6	V
Storage Temperature	Тѕтс	-55	+125	°C
Power Dissipation	PD	_	16	W
Output Current (D.C.)	Ιουτ	-50	+50	mA

\* : Voltages referenced to Vss (= 0 V)

**WARNING:** Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

### RECOMMENDED OPERATING CONDITIONS

Parameter	Notes	s Symbol			Unit	
Falameter	NOLES	Symbol	Min.	Тур.	Max.	Onit
Supply Voltage	*1	Vcc	3.0	3.3	3.6	V
Supply voltage	I	Vss	0	0	0	V
Input High Voltage, All Inputs	*1, 2	Vін	2.0	—	Vcc +0.5	V
Input Low Voltage, All Inputs	*1, 3	VIL	-0.5	—	0.8	V
Ambient Temperature		TA	0	—	+70	°C

\*1. Voltages referenced to Vss (=0V)

\*2. Overshoot limit:  $V_{H}$  (max.) = V<sub>CC</sub> +1.5 V with a pulse-width  $\leq$  5 ns.

\*3. Undershoot limit: V<sub>IL</sub> (min.) = -1.5 V with a pulse-width  $\leq 5$  ns.

**WARNING:** The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated within these ranges.

Always use semiconductor devices within their recommended operating conditionranges. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their FUJITSU representatives beforehand.

## ■ CAPACITANCE

			(Vcc = +3	.3 V, f = 1 MHz,	Γ <sub>A</sub> = +25°C)
Parame	tor	Symbol	Va	Unit	
Falalite		Symbol	Min.	Max.	Onit
	Ao to A11, BA0, BA1	CIN1		99	pF
	RAS, CAS, WE	CIN2		96	pF
	$\overline{CS}_0$ to $\overline{CS}_3$	Сімз		33	pF
Input Capacitance	CKE <sub>0</sub> , CKE <sub>1</sub>	CIN4		59	pF
Input Capacitance	CLK <sub>0</sub> to CLK <sub>3</sub>	CIN5		46	pF
	DQMB <sub>0</sub> to DQMB <sub>7</sub>	CIN6		21	pF
	SCL	CSCL		7	pF
	SA0, SA1, SA2	CSA		7	pF
	SDA	CSDA		7	pF
Input/Output Capacitance	DQ <sub>0</sub> to DQ <sub>63</sub>	CDQ	—	18	pF

## ■ DC CHARACTERISTICS

(At recommended operating conditions unless otherwise noted.) Notes 1, 2, 3

					Value		
Parameter	Notes	Symbol	Condition		Ма	ax.	Unit
				Min.	std. ver.	low ver.	
Operating Current (Average Power Supply Current)	*4	Icc1s	Icc1s Burst Length = 4, $t_{RC}$ = min for BL = 4, $t_{CK}$ = min, One Bank Active, Outputs Open, Address changed up to 3 times during $t_{RC}$ (min.), $0 V \le V_{IN} \le V_{CC}$		960		mA
	4	Icc1d	Burst Length = 4 (each Bank), $t_{RC}$ = min for BL = 4 (each Bank), $t_{CK}$ = min, Two Banks Active, Outputs Open, Address changed up to 3 times during $t_{RC}$ (min.), $0 V \le V_{IN} \le V_{CC}$		1640		mA
	*4	Ісс2р	$\begin{array}{l} CKE=V_{IL},t_{CK}=min,\\ All\;Banks\;Idle,\\ Power\;Down\;Mode,\\ 0\;V\leqV_{IN}\leqV_{CC} \end{array}$	_	32	16	mA
		ICC2PS	$\begin{array}{l} CKE=V_{IL},\\ CLK=V_{IH} \text{ or } V_{IL},\\ All Banks Idle,\\ Power Down Mode,\\ 0 \ V \leq V_{IN} \leq V_{CC} \end{array}$	_	16	8	mA
Precharge Standby Current (Power Supply Current)		Icc2n	$\begin{array}{l} CKE=V_{IH},tck=min,\\ AII\;Banks\;Idle,\\ NOP\;commnands\;only,\\ Input\;signals\;(except\;to\;CMD)\\ are\;changed\;one\;time\;during\\ 3\;clock\;cycles,\\ 0\;V\leqV_{\mathsf{IN}}\leqV_{\mathsf{CC}} \end{array}$	_	— 240		mA
		$\label{eq:cc2NS} \begin{array}{l} CKE = V_{IH},\\ CLK = V_{IH} \mbox{ or } V_{IL},\\ All Banks Idle,\\ Input Signals are Stable,\\ 0 \ V \leq V_{IN} \leq V_{CC} \end{array}$			32		mA

(Continued)

(Continued)

Parameter Not	es Symbo	I Condition		M	ax.	Unit
			Min.	std. ver.	low ver.	_
	Іссзр	$\begin{array}{l} CKE = V_{IL},  tck = min, \\ Any \ Bank \ Active, \\ 0 \ V \leq V_{IN} \leq V_{cc} \end{array}$	_	32	16	mA
Active Standby Current (Power Supply Current)	Іссзря	$\begin{array}{l} CKE = V_{IL},\\ CLK = V_{IH} \text{ or } V_{IL},\\ Any Bank Active,\\ 0 \ V \leq V_{IN} \leq V_{CC} \end{array}$	_	16	8	mA
	*4 Icc3N	CKE = V <sub>IH</sub> , t <sub>CK</sub> = min, Any Bank Active, NOP commands only, Input signals (except to CMD) are changed one time during 3 clock cycles, $0 V \le V_{IN} \le V_{CC}$	_	4	00	mA
	Іссзия	$\begin{array}{l} CKE = V_{IH},\\ CLK = V_{IH} \text{ or } V_{IL},\\ Any Bank Active,\\ 0 \ V \leq V_{IN} \leq V_{CC} \end{array}$	_	3	mA	
Burst Mode Current (Average Power Supply Current)	*4 Icc4	$t_{CK} = min$ , Gapless data, Burst Length = 4, Outputs open, Multiple-banks Active, $0 V \le V_{IN} \le V_{CC}$	_	800		mA
Auto-refresh Current (Average Power Supply Current)	*4 Icc5	Auto Refresh, $t_{CK} = min$ , $t_{RC} = min$ , $0 V \le V_{IN} \le V_{CC}$	_	38	340	mA
Self-refresh Current (Average Power Supply Current)	*4 Icc6	$ \begin{array}{l} \mbox{Self-refresh, tck} = \mbox{min,} \\ \mbox{CKE} \leq 0.2 \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \$	_	16	8	mA
Input Leakage Current (All Inputs)	lu	$I_{LI} = \begin{bmatrix} 0 & V \le V_{IN} \le V_{CC} \\ All & other pins not \\ under test = 0 & V \end{bmatrix} = \begin{bmatrix} -90 & 90 \\ 90 & -90 \end{bmatrix}$		0	μΑ	
Output Leakage Current	Ilo			20		μA
LVTTL Output High Voltage	*5 Vон	Іон = -2.0 mA	2.4			V
LVTTL Output Low Voltage	*5 Vol	loL = +2.0 mA	_	0	.4	V

Notes: \*1. An initial pause (DESL on NOP) of 200 μs is required after power-on followed by a minimum of eight Auto-refresh cycles.

\*2. Values of Icc1s, Icc1D and Icc4 are for when one side of the double-sided module is in standby mode (Icc2N) and the other side is in active.

\*3. DC characteristics is the Serial PD standby state ( $V_{IN} = GND$  or  $V_{CC}$ ).

\*4. Icc depends on the output termination, load conditions, clock cycle rate and signal clock rate. The specified values are obtained with the output open and no termination resistors.

\*5. Voltages referenced to  $V_{SS}$  (= 0 V)

## ■ AC CHARACTERISTICS

(SDRAM Component Specifications) Notes 1, 2, 3

### (1) BASE CHARACTERISTICS

(At recommended operating conditions unless otherwise noted.)

No.	Parameter No	otes	Symbol		S064CZ -102L		S064CZ -103L	Unit
			-	Min.	Max.	Min.	Max.	
1	Clock Period	CL = 2	tск2	10	—	15	—	ns
	Clock Fellou	CL = 3	<b>t</b> скз	10	—	10	_	115
2	Clock High Time		tсн	3	—	3	—	ns
3	Clock Low Time		tc∟	3	—	3	—	ns
4	Input Setup Time		tsi	2	—	2	—	ns
5	Input Hold Time		tн	1	—	1	—	ns
6	Output Valid from Clock *4, *5	CL = 2	t <sub>AC2</sub>	_	6	_	8	20
0	$(t_{CLK} = min)$ 4, 5	CL = 3	tасз	_	6		6	ns
7	Output in Low-Z		t∟z	0	_	0	_	ns
8	Output in High-Z *6	CL = 2	t <sub>HZ2</sub>	3	6	3	8	
0	Output in High-Z *6	CL = 3	<b>t</b> HZ3	3	6	3	6	ns
9	Output Hold Time		tон	3	—	3	—	ns
10	Time between Refresh		<b>t</b> REF	_	65.6		65.6	ms
11	Transition Time		t⊤	0.5	2	0.5	2	ns
12	CKE Setup Time for Power Down E	xit Time	<b>t</b> CKSP	3	—	3	—	ns

### (2) BASE VALUES FOR CLOCK COUNT/LATENCY

No.	Parameter	Notes	Symbol	MB8516 -102/-	S064CZ -102L		S064CZ -103L	Unit
			-	Min.	Max.	Min.	Max.	
1	RAS Cycle Time	*7	trc	70	—	70	—	ns
2	RAS Precharge Time		<b>t</b> RP	20	—	20	—	ns
3	RAS Active Time		tras	50	110000	50	110000	ns
4	RAS to CAS Delay Time	*8	trcd	20	_	20	—	ns
5	Write Recovery Time		twr	10	—	10	—	ns
6	Data-in to Precharge Lead Time		<b>t</b> dpl	10	_	10	_	ns
7	Data-in to Active/Refresh Command Period	CL = 2	tdal2	1 cyc + t <sub>RP</sub>		1 cyc + t <sub>RP</sub>		ns
/	Data-in to Active/Reliesh Command Feriou	CL = 3	<b>t</b> dal3	2 cyc + t <sub>RP</sub>	—	2 cyc + t <sub>RP</sub>	_	115
8	Mode Register Set Cycle Time	Mode Register Set Cycle Time		20	—	20	—	ns
9	RAS to RAS Bank Active Delay Time		<b>t</b> rrd	20		20		ns

### (3) CLOCK COUNT FORMULA (\*9)

 $Clock \geq \frac{Base \ Value}{Clock \ Period} \ (Round \ off \ a \ whole \ number)$ 

### (4) LATENCY (The latency values on these parameters are fixed regardless of clock period.)

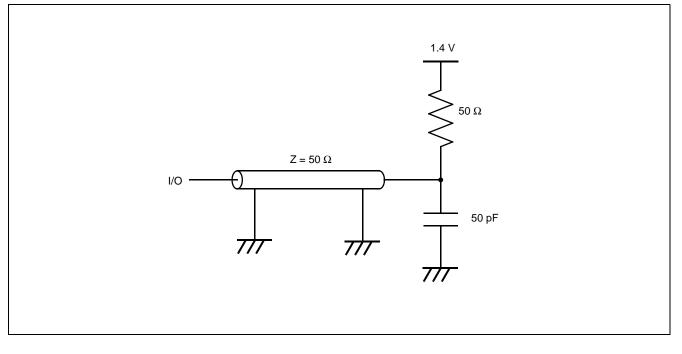
No.	Parameter		Symbol	MB8516S064CZ -102/-102L	MB8516S064CZ -103/-103L	Unit	
1	CKE to Clock Disable			1	1	Cycle	
2	DQM to Output in High-Z			2	2	Cycle	
3	DQM to Input Data Delay		IDQD	0	0	Cycle	
4	Last Output to Write Command Delay		lowd	2	2	Cycle	
5	Write Command to Input Data Delay		ldwd	0	0	Cycle	
6	Precharge to Output in High-Z Delay $CL = 2$ $CL = 2$		ROH2	2	2	Cycle	
6			Ігонз	3	3		
7	Burst Stop Command to Output in High-Z Delay $\frac{CL = 2}{CL = 3}$		Івзн2	2	2	Cycle	
			Івѕнз	3	3		
8	CAS to CAS Delay (min)			1	1	Cycle	
9	CAS Bank Delay (min)		Ісвр	1	1	Cycle	

- Notes: \*1. An initial pause (DESL on NOP) of 200 μs is required after power-up followed by a minimum of eight Auto-refresh cycles.
  - \*2. 1.4 V or V<sub>REF</sub> is the reference level for measuring timing of signals. Transition times are measured between V<sub>IH</sub> (min) and V<sub>IL</sub> (max).
  - \*3. AC characteristics assume  $t_T = 1$  ns and 50 pF of capacitance load.
  - \*4. Assumes tRCD is satisfied.
  - \*5. tac also specifies the access time at burst mode except for first access.
  - \*6. Specified where output buffer is no longer driven.
  - \*7. Actual clock count of trc (Irc) will be sum of clock count of tras (Iras) and trp (Irp).
  - \*8. Operation within the tRCD (min) ensures that access time is determined by tRCD (min) +tAC (max); if tRCD is greater than the specified tRCD (min), access time is determined by tAC.
  - \*9. All base values are measured from the clock edge at the command input to the clock edge for the next command input.
    - All clock counts are calculated by a simple formula:

clock count equals base value divided by clock period (round off to a whole number).

\*Source: See MB81F64842C Data Sheet for details on the electrical.

### AC OPERATING TEST CONDITION (Example of AC Test Load Circuit)



### ■ SERIAL PRESENCE DETECT(SPD) FUNCTION

#### 1. PIN DESCRIPTIONS

#### SCL (Serial Clock)

SCL input is used to clock all data input/output of SPD.

#### SDA (Serial Data)

SDA is a common pin used for all data input/output of SPD. The SDA pull-up resistor is required due to the open-drain output.

#### SA<sub>0</sub>, SA<sub>1</sub>, SA<sub>2</sub> (Address)

Address inputs are used to set the least significant three bits of the eight bits slave address. The address inputs must be fixed to select a particular module and the fixed address of each module must be different each other.

#### 2. SPD OPERATIONS

#### **CLOCK and DATA CONVENTION**

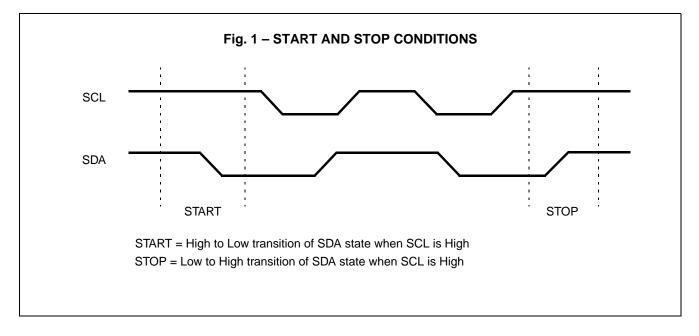
Data states on the SDA can change only during SC L= Low. SDA state changes during SCL = High are indicated start and stop conditions. Refer to Fig. 1 below.

#### START CONDITION

All commands are preceded by a start condition, which is a transition of SDA state from High to Low when SCL = High. SPD will not respond to any command until this condition has been met.

#### **STOP CONDITION**

All read or write operation must be terminated by a stop condition, which is a transition of SDA state from Low to High when SCL = High. The stop condition is also used to make the SPD into the state of standby power mode after a read sequence.



#### ACKNOWLEDGE

Acknowledge is a software convention used to indicate successful data transfer. The transmitting device, either master or slave, will release the bus after transmitting eight bits. During the ninth clock cycle the receiver will put the SDA line to Low in order to acknowledge that it received the eight bits of data.

The SPD will respond with an acknowledge when it received the start condition followed by slave address issued by master.

In the read operation, the SPD will transmit eight bits of data, release the SDA line and monitor the line for an acknowledge. If an acknowledge is detected and no stop condition is issued by master, the SPD will continue to transmit data. If an acknowledge is not detected, the SPD will terminated further data transmissions. The master must then issue a stop condition to return the SPD to the standby power mode.

In the write operation, upon receipt of eight bits of data the SPD will respond with an acknowledge, and await the next eight bits of data, again responding with an acknowledge until the stop condition is issued by master.

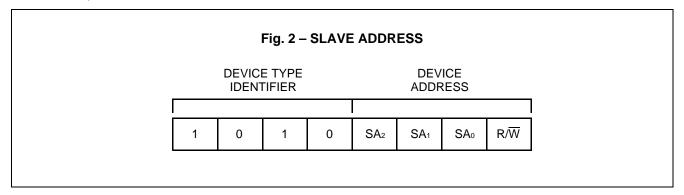
#### SLAVE ADDRESS ADDRESSING

Following a start condition, the master must output the eight bits slave address. The most significant four bits of the slave address are device type identifier. For the SPD this is fixed as 1010[B]. Refer to the Fig. 2 below.

The next three significant bits are used to select a particular device. A system could have up to eight SPD devices —namely up to eight modules— on the bus. The eight addresses for eight SPD devices are defined by the state of the SA<sub>0</sub>, SA<sub>1</sub> and SA<sub>2</sub> inputs.

The last bit of the slave address defines the operation to be performed. When  $R/\overline{W}$  bit is "1", a read operation is selected, when  $R/\overline{W}$  bit is "0", a write operation is selected.

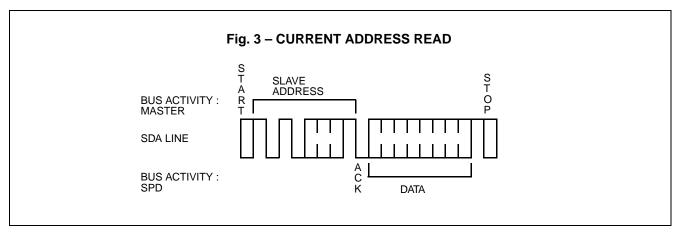
Following the start condition, the SPD monitors the SDA line comparing the slave address being transmitted with its slave address (device type and state of SA<sub>0</sub>, SA<sub>1</sub>, and SA<sub>2</sub> inputs). Upon a correct compare the SPD outputs an acknowledge on the SDA line. Depending on the state of the R/W bit, the SPD will execute a read or write operation.



#### 3. READ OPERATIONS

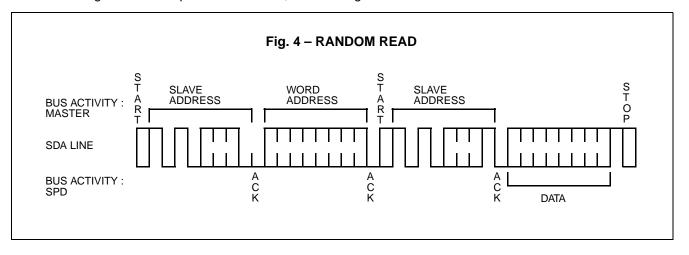
#### CURRENT ADDRESS READ

Internally the SPD contains an address counter that maintains the address of the last data accessed, incremented by one. Therefore, if the last access (either a read or write operation) was to address(n), the next read operation would access data from address(n+1). Upon receipt of the slave address with the R/W bit = "1", the SPD issues an acknowledge and transmits the eight bits of data during the next eight clock cycles. The master terminates this transmission by issuing a stop condition, omitting the ninth clock cycle acknowledge. Refer to Fig. 3 for the sequence of address, acknowledge and data transfer.



#### RANDOM READ

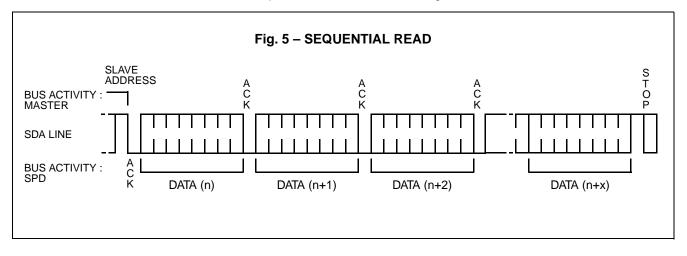
Random Read operations allow the master to access any memory location in a random manner. Prior to issuing the slave address with the R/W bit = "1", the master must first perform a "dummy" write operation on the SPD. The master issues the start condition, and the slave address followed by the word address. After the word address acknowledge, the master immediately reissues the start condition and the slave address with the R/W bit = "1". This will be followed by an acknowledge from the SPD and then by the eight bits of data. The master terminates this transmission by issuing a stop condition, omitting the ninth clock cycle acknowledge. Refer to Fig. 4 for the sequence of address, acknowledge and data transfer.



#### SEQUENTIAL READ

Sequential Read can be initiated as either a current address read or random read. The first data are transmitted as with the other read mode, however, the master now responds with an acknowledge, indicating it requires additional data. The SPD continues to output data for each acknowledge received. The master terminates this transmission by issuing a stop condition, omitting the ninth clock cycle acknowledge. Refer to Fig. 5 for the sequence of address, acknowledge and data transfer.

The data output is sequential, with the data from address(n) followed by the data from address(n+1). The address counter for read operations increments all address bits, allowing the entire memory contents to be serially read during one operation. At the end of the address space (address 255), the counter "rolls over" to address 0 and the SPD continues to output data for each acknowledge received.



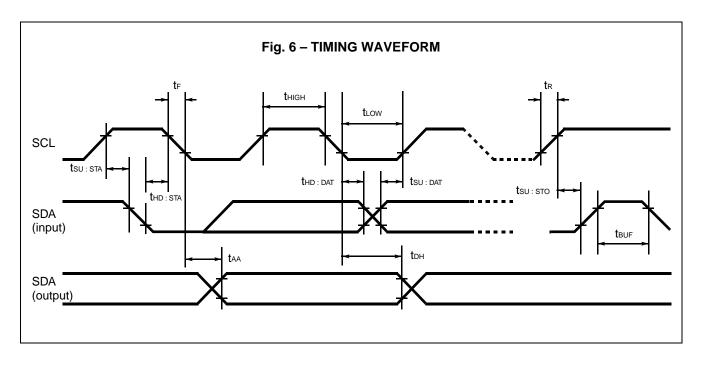
### 4. DC CHARACTERISTICS

Parameter	Note	Symbol	Condition	Value		Unit
Farameter	Note		Condition	Min.	Max.	Unit
Input Leakage Current		Sili	$0~V \leq V_{\text{IN}} \leq V_{\text{CC}}$	-10	10	μA
Output Leakage Current		SILO	$0 \text{ V} \leq \text{V}_{\text{OUT}} \leq \text{V}_{\text{CC}}$	-10	10	μA
Output Low Voltage	*1	Svol	lo∟ = 3.0 mA	—	0.4	V

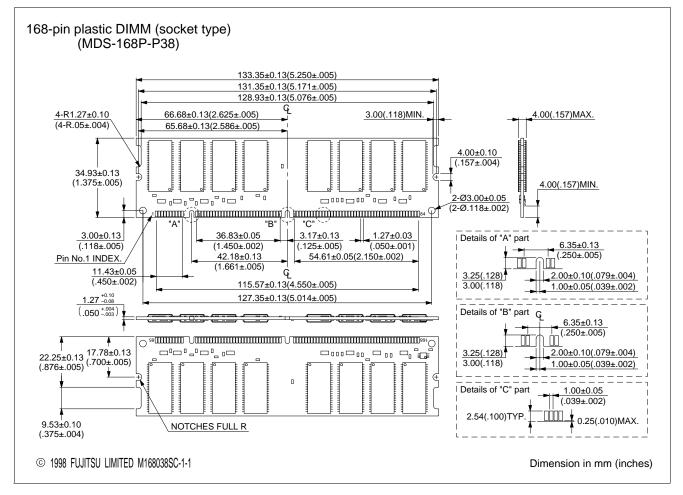
Note: \*1. Referenced to Vss.

### 5. AC CHARACTERISTICS

No.	Parameter	Symbol	Va	Unit	
INO.		Symbol	Min.	Max.	Onit
1	SCL Clock Frequency	fsc∟	—	100	KHz
2	Noise Suppression Time Constant at SCL, SDA Inputs	Τι	_	100	ns
3	SCL Low to SDA Data Out Valid	taa	—	3.5	μs
4	Time the Bus Must Be Free Before a New Transmission Can Start	<b>t</b> BUF	4.7	_	μs
5	Start Condition Hold Time	<b>t</b> hd:sta	4.0	_	μs
6	Clock Low Period	tLow	4.7	_	μs
7	Clock High Period	tніgн	4.0	—	μs
8	Start Condition Setup Time	tsu:sta	4.7	_	μs
9	Data in Hold Time	thd:dat	0	_	μs
10	Data in Setup Time	tsu:dat	250	—	ns
11	SDA and SCL Rise Time	tR		1	μs
12	SDA and SCL Fall Time	t⊧		300	ns
13	Stop Condition Setup Time	tsu:sto	4.7	—	μs
14	Data Out Hold Time	tон	100	_	ns
15	Write Cycle Time	twr		15	ms



### PACKAGE DIMENSION



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